Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/785,259	OHKAWA ET AL.	
Examiner	Art Unit	
B. Chen	1762	

	SEARCHED						
Class	Subclass	Date	Examiner				
updated	previous	2/24/2006	ВС				
	<u>. </u>						

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
east		2/24/2006	ВС		
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